

## MM5280 4096-Bit (4096 × 1) Dynamic RAM

### General Description

National's MM5280 is a 4096 word by 1 bit dynamic RAM. It incorporates the latest memory design features and can be used in a wide variety of applications, from those which require very high speed to ones where low cost and large bit capacity are the prime criteria.

The MM5280 must be refreshed every 2 ms. This can be accomplished by performing a read cycle at each of the 64 row addresses (A0–A5). The chip select input can be either high or low for refresh.

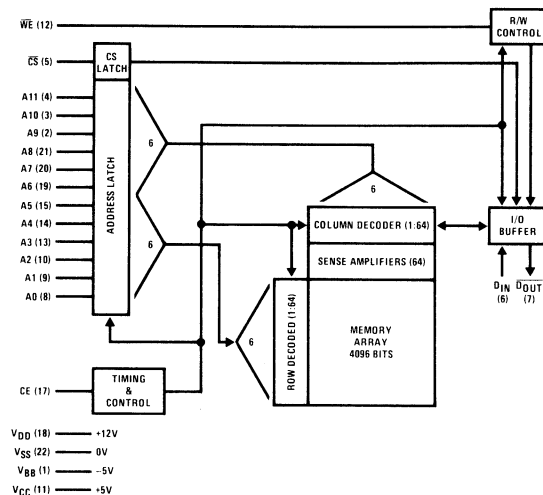
The MM5280 has been designed with minimum production costs as a prime criterion. It is fabricated using N-channel silicon gate MOS technology, which is an ideal choice for high density integrated circuits. The MM5280 uses a single transistor cell to minimize the device area. The single device cell, along with unique design features

in the on-chip peripheral circuits, yields a high performance memory device.

### Features

- Organization: 4096 × 1
- Access time 200 ns maximum
- Cycle time 400 ns minimum
- Easy system interface
  - One high voltage input—chip enable
  - TTL compatible—all other inputs and output
- Address registers on-chip
- TRI-STATE<sup>®</sup> output
- Simple read-modify-write operation
- Industry standard pin configuration

### Block Diagram



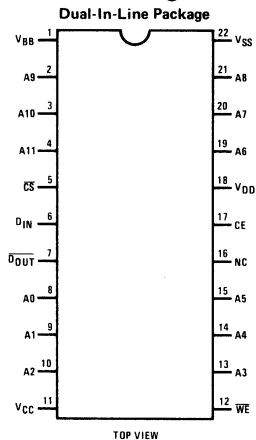
Memory Inverts From Data In to Data Out

#### Pin Names

A0–A11	Address Inputs *	V <sub>BB</sub>	Power (-5V)
CE	Chip Enable	V <sub>CC</sub>	Power (+5V)
CS	Chip Select	V <sub>DD</sub>	Power (+12V)
D <sub>IN</sub>	Data Input	V <sub>SS</sub>	Ground
D <sub>OUT</sub>	Data Output	WE	Write Enable
NC	Not Connected		

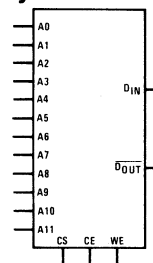
\* Refresh Address A0–A5

### Connection Diagram



Order Number MM5280N Order Number MM5280J  
 See NS Package N22A See NS Package J22A

### Logic Symbol



## Absolute Maximum Ratings (Note 1)

Storage Temperature	-65°C to +150°C
All Input or Output Voltages with Respect to the Most Negative Supply Voltage, $V_{BB}$	-0.3V to +25V
Supply Voltages $V_{DD}$ , $V_{CC}$ and $V_{SS}$ with Respect to $V_{BB}$	-0.3V to +20V
Power Dissipation	1.25W

## Operating Conditions

	MIN	MAX	UNITS
Operating Temperature Range	0	+70	°C
$V_{DD}$ Voltage	10.8	13.2	V
$V_{CC}$ Voltage	4.5	5.5	V
$V_{BB}$ Voltage	-5.5	-4.5	V

## DC Electrical Characteristics

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{DD} = +12\text{V} \pm 10\%$ ,  $V_{CC} = +5\text{V} \pm 10\%$ ,  $V_{BB}$  (Note 2) =  $-5\text{V} \pm 10\%$ ,  $V_{SS} = 0\text{V}$ , unless otherwise noted

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
$I_{LI}$	Input Load Current	$V_{IN} = 0\text{V}$ to $V_{IH}$ max, (All Inputs Except CE)		0.01	10	$\mu\text{A}$
$I_{LC}$	Input Load Current	$V_{IN} = 0\text{V}$ to $V_{IHC}$ max		0.01	10	$\mu\text{A}$
$I_{LO1}$	Output Leakage Current Up For High Impedance State	$CE = V_{ILC}$ or $\overline{CS} = V_{IH}$ , $V_O = 0\text{V}$ to 5.25V		0.01	10	$\mu\text{A}$
$I_{DD1}$	$V_{DD}$ Supply Current During CE "OFF"	$CE = -1\text{V}$ to +6V, Note 4		110	300	$\mu\text{A}$
$I_{DD2}$	$V_{DD}$ Supply Current During CE "ON"	$CE = V_{IHC}$ , $T_A = 25^\circ\text{C}$		20	40	mA
$I_{DDAV1}$	Average $V_{DD}$ Current	$T_A = 25^\circ\text{C}$ Cycle Time = 400 ns, $t_{CE} = 230$ ns		35	60	mA
$I_{DDAV2}$	Average $V_{DD}$ Current	$T_A = 25^\circ\text{C}$ Cycle Time = 1000 ns, $t_{CE} = 230$ ns		15	30	mA
$I_{CC1}$	$V_{CC}$ Supply Current During CE "OFF"	$CE = V_{ILC}$ or $\overline{CS} = V_{IH}$ (Note 5)		0.01	10	$\mu\text{A}$
$I_{BB}$	$V_{BB}$ Supply Current Average			5	100	$\mu\text{A}$
$V_{IL}$	Input Low Voltage	$t_T = 20$ ns (Figure 4)	-1.0		0.6	V
$V_{IH}$	Input High Voltage		2.4		$V_{CC}+1$	V
$V_{ILC}$	CE Input Low Voltage		-1.0		1.0	V
$V_{IHC}$	CE Input High Voltage		$V_{DD}-1$		$V_{DD}+1$	V
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.0$ mA	0.0		0.45	V
$V_{OH}$	Output High Voltage	$I_{OH} = -2.0$ mA	2.4		$V_{CC}$	V

**Note 1:** "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" provides conditions for actual device operation.

**Note 2:** The only requirement for the sequence of applying voltage to the device is that  $V_{DD}$ ,  $V_{CC}$ , and  $V_{SS}$  should never be 0.3V more negative than  $V_{BB}$ .

**Note 3:** Typical values are for  $T_A = 25^\circ\text{C}$  and nominal power supply voltages.

**Note 4:** The  $I_{DD}$  and  $I_{CC}$  currents flow to  $V_{SS}$ . The  $I_{BB}$  current is the sum of all leakage currents.

**Note 5:** During CE "ON"  $V_{CC}$  supply current is dependent on output loading,  $V_{CC}$  is connected to output buffer only.

## AC Electrical Characteristics $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$ , $V_{DD} = 12\text{V} \pm 10\%$ , $V_{CC} = 5\text{V} \pm 10\%$ , $V_{BB} = -5\text{V} \pm 10\%$

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
<b>READ, WRITE, READ/MODIFY/WRITE, AND REFRESH CYCLE</b>						
$t_{REF}$	Time Between Refresh				2	ms
$t_{AC}$	Address to CE Set-Up Time	$t_{AC}$ is Measured From End of Address Transition	0			ns
$t_{AH}$	Address Hold Time		50			ns
$t_{CC}$	CE "OFF" Time		130			ns
$t_T$	CE Transition Time		10		40	ns
$t_{CF}$	CE "OFF" to Output High Impedance State		0			ns
<b>READ CYCLE</b>						
$t_{CY}$	Cycle Time		400			ns
$t_{CE}$	CE "ON" Time		230		3000	ns
$t_{CO}$	CE Output Delay	$C_{LOAD} = 50$ pF, Load = 1 TTL Gate, Ref = 2.0V,			180	ns
$t_{ACC}$	Address to Output Access	$t_{ACC} = t_{AC} + t_{CO} + 1 t_T$			200	ns
$t_{WL}$	CE to $\overline{WE}$		0			ns
$t_{WC}$	$\overline{WE}$ to CE "ON"		0			ns

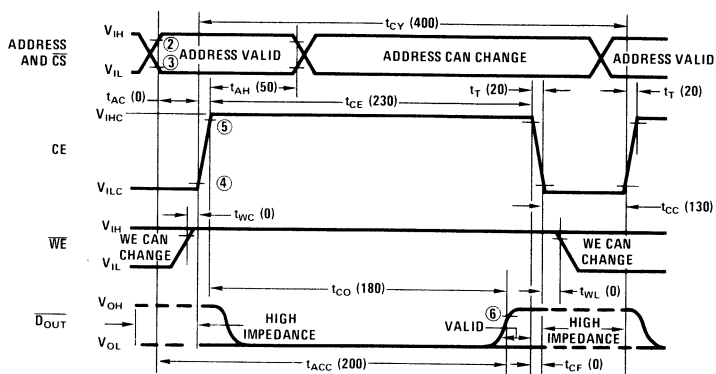
## AC Electrical Characteristics (Continued)

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{DD} = 12\text{V} \pm 10\%$ ,  $V_{CC} = 5\text{V} \pm 10\%$ ,  $V_{BB} = -5\% \pm 10\%$

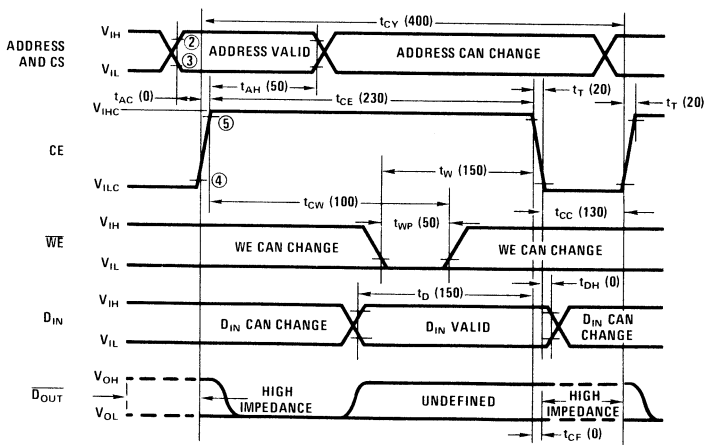
SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
<b>WRITE CYCLE</b>						
$t_{CY}$	Cycle Time		400			ns
$t_{CE}$	CE "ON" Time		230		3000	ns
$t_{W}$	$\overline{WE}$ to CE "OFF"		150			ns
$t_{CW}$	CE to $\overline{WE}$	$t_T = 20$ ns	100			ns
$t_D$	$D_{IN}$ to CE Set-Up		150			ns
$t_{DH}$	$D_{IN}$ Hold Time		0			ns
$t_{WP}$	$\overline{WE}$ Pulse Width		50			ns

## Switching Time Waveforms

Read and Refresh Cycle<sup>①</sup>



Write Cycle



Note 1: For refresh cycle, row and column addresses must be stable before  $t_{AC}$  and remain stable for entire  $t_{AH}$  period.

Note 2:  $V_{IL}$  max is the reference level for measuring timing of the address,  $\overline{CS}$  and  $D_{IN}$ .

Note 3:  $V_{IH}$  min is the reference level for measuring timing of the addresses,  $\overline{CS}$  and  $D_{IN}$ .

Note 4:  $V_{SS} + 2.0\text{V}$  is the reference level for measuring timing of CE.

Note 5:  $V_{DD} - 2\text{V}$  is the reference level for measuring timing of CE.

Note 6:  $V_{SS} + 2.0\text{V}$  is the reference level for measuring the timing of  $D_{OUT}$  for a high output.

